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PATTERSON & SHERIDAN, LLP 3040 POST OAK BOULEVARD, SUITE 1500

HOUSTON TX 77056

Patent No.

: 6,911,399 B2

Inventor(s)

: Wei Liu, et al.

Issued

: June 28, 2005

For

METHOD OF CONTROLLING

CRITICAL DIMENSION MICROLOADING OF PHOTORESIST TRIMMING PROCESS BY

SELECTIVE SIDEWALL POLYMER

DEPOSITION

Doc. No.

APPM/7989/ETCH/SILICON/JB

To Whom It May Concern:

The Certificate of Correction issued on	April 11, 2006, issued in error, in that
error(s) was made in identifying the patent number	and/or keying text/corrections, i.e.:

The issue date in the heading of cofc has been incorrectly entered on SB44 form submitted by attorney. In future instances, in the heading of the cofc the patent issue date should be displayed not the filing date or the date of filing of the request for cofc.

Therefore, a certificate of correction will be issued to correct (supersede) the Certificate of Correction containing error(s), made during preparation of the Certificate of Correction, as noted above.

No further response is required, from applicants (attorney). However, errors discovered by attorney, other than as noted and described above, should be noted on *a copy* of the Certificate of Correction that was issued in error, accompanied by a signed transmittal letter and submitted directed to this Branch.

Antonio Johnson (703) 308-8331 For Cecelia Newman, Supervisor Decisions & Certificates of Correction Branch (703) 305-8309 / 703-303-8228 cbn